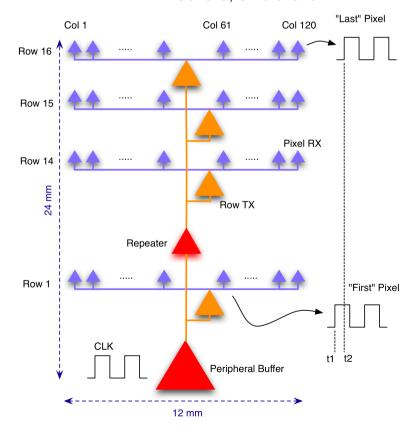


## Design and test of clock distribution circuits for the Macro Pixel ASIC

L. Gaioni<sup>1</sup>, F. De Canio<sup>2,3</sup>, M. Manghisoni<sup>1,3</sup>, L. Ratti<sup>2,3</sup>, V. Re<sup>1,3</sup>, G. Traversi<sup>1,3</sup>, A. Marchioro<sup>4</sup>, K. Kloukinas<sup>4</sup>

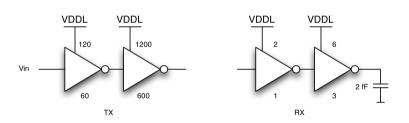
<sup>1</sup> University of Bergamo Department of Engineering and Applied Sciences Dalmine (BG), Italy <sup>2</sup> University of Pavia, Department of Electrical, Computer and Biomedical Engineering, Pavia, Italy <sup>3</sup> INFN Sezione di Pavia Pavia, Italy <sup>4</sup> CERN European Organization for Nuclear Research Geneva, Switzerland

- Low-power architectures are required to meet the power budget constraint of the Macro Pixel ASIC, the readout chip for the so called Pixel -Strip module of the CMS tracker
- ✓ A 65nm CMOS test chip, including the clock distribution circuits for the MPA, has been fabricated and tested
- Two possible implementations have been investigated, based on CMOS buffers supplied with reduced VDD and on reduced swing drivers
- ✓ The proposed solution is based on a row clock distribution scheme

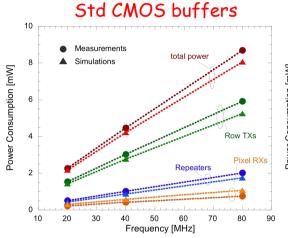


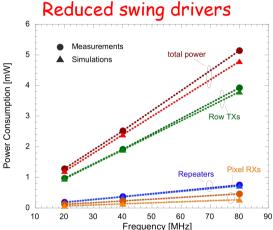
## Design and test of clock distribution circuits for the Macro Pixel ASIC

Standard CMOS buffers as TXs and RXs, supplied by VDDL=800 mV

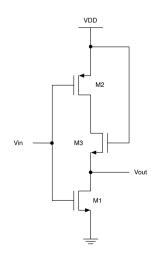


Reduced swing driver supplied at VDD=1.2 V





Maximum skew @ 40 MHz





up to 60% power saving with a 0.8V chip supply voltage

Max. skew < 1 ns